

# Quad Sine-Wave Clock Buffer With LDO

Check for Samples: CDC3S04

#### **FEATURES**

- 1:4 Low-Jitter Clock Buffer
- Single-Ended Sine-Wave Clock Input and **Outputs**
- **Ultralow Phase Noise and Standby Current**
- **Individual Clock Request Inputs for Each Output**
- On-Chip Low-Dropout Output (LDO) for Low-Noise TCXO Supply
- Serial I<sup>2</sup>C Interface (Compatible With High-Speed Mode, 3.4 Mbit/s)
- 1.8-V Device Power Supply
- Wide Temperature Range, -30°C to 85°C
- ESD Protection: 2 KV HBM, 750 V CDM, and 100 V MM
- Small 20-Pin Chip-Scale Package: 0.4-mm Pitch WCSP (1.6 mm × 2 mm)

#### **APPLICATIONS**

- **Cellular Phones**
- **Smart Phones**
- **Mobile Handsets**
- **Portable Systems**
- Wireless Modems Including GPS, WLAN, W-BT, D-TV, DVB-H, FM Radio, WiMAX, and System Clock

#### DESCRIPTION

The CDC3S04 is a four-channel low-power low-jitter sine-wave clock buffer. It can be used to buffer a single master clock to multiple peripherals. The four sine-wave outputs (CLK1-CLK4) are designed for minimal channel-to-channel skew and ultralow additive output jitter.

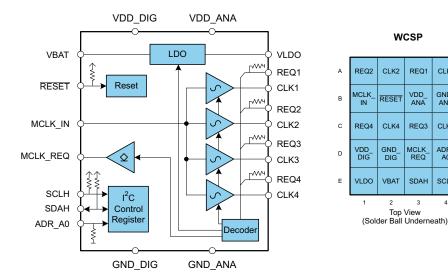
Each output has its own clock request inputs which enables the dedicated clock output. These clock requests are active-high (can also be changed to be active-low via I<sup>2</sup>C), and an output signal is generated that can be sent back to the master clock to request clock (MCLK REQ). MCKL REQ open-source output and supports the wired-OR function (default mode). It needs an external pulldown resistor. MCKL\_REQ can be changed to wired-AND or push-pull functionality via I<sup>2</sup>C.

The CDC3S04 also provides an I<sup>2</sup>C interface (Hs-mode) that can be used to enable or disable the outputs, select the polarity of the REQ inputs, and allow control of internal decoding.

The CDC3S04 features an on-chip high-performance LDO that accepts voltages from 2.3 V to 5.5 V and outputs a 1.8-V supply. This 1.8-V supply can be used to power an external 1.8-V TCXO. It can be enabled or disabled for power saving at the TCXO.

CLK1

CLK3





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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

# **DESCRIPTION (CONTINUED)**

A low signal at the  $\overline{\text{RESET}}$  input switches the outputs CLK1 and CLK4 into the default state. In this <u>configuration</u>, CLK1 and CLK4 are ON (see <u>Table 1</u>); the remaining device function is not affected. Also, the RESET input provides a glitch filter which rejects spikes of typical 300 ns on the RESET line to preserve false reset. A complete device reset to the default condition can be initiated by a power-up cycle of  $V_{DD\ DIG}$ .

The CDC3S04 operates from two 1.8-V supplies. There is a core supply (VDD\_DIG/GND\_DIG) for the core logic and a low-noise analog supply (VDD\_ANA/GND\_ANA) for the sine-wave outputs. The CDC3S04 is designed for sequence-less power up. Both supply voltages may be applied in any order.

The CDC3S04 is offered in a 0.4-mm pitch WCSP package (1.6 mm  $\times$  2 mm) and is optimized for low standby current (0.5  $\mu$ A). It is characterized for operation from  $-30^{\circ}$ C to  $85^{\circ}$ C.

#### **DEVICE INFORMATION**

#### **PIN FUNCTIONS**

NAME	BALL NO.	TYPE	FUNCTION
ADR_A0	D4	Input	Selectable address bit A0 of slave-address register; internal 500-kΩ pulldown resistor
CLK1	A4	Output	Clock output 1
CLK2	A2	Output	Clock output 2
CLK3	C4	Output	Clock output 3
CLK4	C2	Output	Clock output 4
GND_ANA	B4	Ground	Ground for sine-wave buffer
GND_DIG	D2	Ground	Ground for core logic
MCLK_IN	B1	Input	Master clock input
MCLK_RE Q	D3	Output	Clock request to the master clock source; active-high; open-source output for wired-OR connection (default condition). Can be changed to push-pull output or wired-AND output via I <sup>2</sup> C.
REQ1	А3	Input	Clock request from peripheral 1; internal 500-kΩ pulldown resistor
REQ2	A1	Input	Clock request from peripheral 2; internal 500-kΩ pulldown resistor
REQ3	C3	Input	Clock request from peripheral 3; internal 500-kΩ pulldown resistor
REQ4	C1	Input	Clock request from peripheral 4; internal 500-kΩ pulldown resistor
RESET	B2	Input	Peripheral reset signal provided by application processor. The signal is active-low and switches CLK1 and CLK4 outputs to ON (see Table 1). On-chip LDO is enabled. Internal 1-M $\Omega$ pullup resistor and 300-ns (typ) glitch filter.
SCLH	E4	Input	$I^2C$ clock input – Hs-mode. Internal 1-M $\Omega$ pullup resistor
SDAH	E3	Input/output	I <sup>2</sup> C data input/output – Hs-mode. Internal 1-MΩ pullup resistor
VBAT	E2	Power	Supply pin to internal LDO
VDD_ANA	В3	Power	1.8-V power supply for sine-wave buffer
VDD_DIG	D1	Power	1.8-V power supply for core logic. Power up of VDD_DIG resets the whole device to the default condition.
VLDO	E1	Output	1.8-V supply for external TCXO; LDO is enabled if RESET (default mode) or REQx is active. LDO is not enabled if only VBAT is on.



#### **FUNCTION SELECTION TABLES**

Table 1. Reset and Request (REQx) Conditions for Clock Outputs (1)

RESET <sup>(2)</sup>	PRIORITY BIT <sup>(3)</sup>	CLK1	CLK2	CLK3	CLK4
0	0	On	Controlled by REQ2	Controlled by REQ3	05
0	1	On	Controlled by REQ2INT	Controlled by REQ3INT	On
4	0	Controlled by REQ1	Controlled by REQ2	Controlled by REQ3	Controlled by REQ4
1	1 Controlled by REQ1INT		Controlled by REQ2INT	Controlled by REQ3INT	Controlled by REQ4INT

# Table 2. Request Signal Condition for Clock Outputs (1)

REQ-Signals (2)	REQx (REQ1/2/3/4)	CLKx (CLK1/2/3/4)	MCLK_REQ	LDO <sup>(3)</sup>
Active-low	0	Clock	High	On
	1	Disabled to high	Low (if all REQx are high)	Off (if all REQx are high)
A ativo high	0	Disabled to high (4)	Low (if all REQx are low)	Off (if all REQx are low)
Active-high	1	Clock <sup>(4)</sup>	High	On

Shaded cells show the default setting after power up.

- The LDO is controlled by an on-chip decoder, but can also be SW controlled (see Table 3, Byte 2, Bits 4-5).
- CLK1 and CLK4 are ON after device power up (default condition). CLK2 and CLK3 are controlled by external REQ2 and REQ3, respectively.

#### **POWER GROUPS**

NAME	DESCRIPTION
VBAT	Supply pin for LDO provided by main battery. LDO is not working if only VBAT is on.
VLDO	1.8-V low-drop output voltage for external TCXO. LDO is enabled if VBAT and VDD_DIG are on and REQx or RESET is active (see Table 2).
VDD_DIG	1.8-V power supply for core logic and I <sup>2</sup> C logic. VDD_DIG must be supplied for correct device operation. Power up of VDD_DIG resets the whole device to the default condition.
VDD_ANA	1.8-V power supply for sine-wave buffers. For correct sine-wave buffer function, all three power supplies (VBAT, V <sub>DD_DIG</sub> and V <sub>DD_ANA</sub> ) must be on. But, V <sub>DD_ANA</sub> can be switched on and off at any time. If off, the sine-wave outputs are switched to high-impedance.

#### POWER-UP SEQUENCE

The CDC3S04 is designed for sequence-less power up. VBAT,  $V_{DD\_DIG}$ , and  $V_{DD\_ANA}$  may be applied in any order. Recommended power-on sequence is VBAT first, followed by  $V_{DD\_DIG}$  and  $V_{DD\_ANA}$ . Recommended power-off sequence is in reverse order.

 <sup>(1)</sup> Shaded cells show the default setting after power up.
 (2) RESET resets REQ1PRIO/REQ4PRIO and REQ1INT/REQ4INT bits to their default values (CLK1/4 is ON) but does not change the remaining internal SW bits. During RESET, any I<sup>2</sup>C operation is blocked until RESET is deactivated. A minimum pulse duration of 500 ns must be applied to activate RESET (the internal glitch-filter suppresses spikes of typical 300 ns).

Priority bit defines if the external control pins (HW controlled) or the SW bits (SW controlled) have priority. It can be set in the configuration register, Byte 2, Bits 0-3.

Polarity of REQ1, REQ2, REQ3, and REQ4 are register-configurable via 1<sup>2</sup>C (see Table 3, Byte 0, Bits 0–3). Default setting is



# **ABSOLUTE MAXIMUM RATINGS**

over operating free-air temperature range (unless otherwise noted) (1)

		VALUE	UNIT
$V_{DD\_ANA} \ V_{DD\_DIG}$	Supply voltage range	-0.5 to 2.5	٧
$V_{BAT}$	Battery supply voltage range	–0.5 to 6.5	٧
VI	Input voltage range <sup>(2) (3)</sup>	-0.5 to V <sub>DD</sub> + 0.5	V
Vo	Output voltage range (2) (3)	–0.5 to V <sub>DD</sub> + 0.5	٧
$V_{LDO}$	Output voltage range	–0.5 to V <sub>BAT</sub> + 0.5	٧
	Input current $(V_i < 0, V_i > V_{DD})$	±20	mA
Io	Continuous output current	±20	mA
I <sub>LDO</sub>	Continuous output current	±20	mA
T <sub>stg</sub>	Storage temperature range	-65 to 150	°C

- (1) Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute—maximum—rated conditions for extended periods may affect device reliability.
- (2) The input and output negative voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
- (3) The input V<sub>I</sub> and output V<sub>O</sub> positive voltages are limited to the absolute maximum rating for V<sub>DD</sub> = 2.5 V.

# THERMAL CHARACTERISTICS for 20-pin WCSP (YFF)(1)

	PARAMETER	AIRFLOW (Ifm)	20-PIN WCSP	UNIT
		0	71	
$T_{JA}$	Thermal resistance, junction-to-ambient	200	62	°C/W
		400	59	
$T_{JC}$	Thermal resistance, junction-to- case	_	17.5	°C/W
$T_JB$	Thermal resistance, junction-to-board	_	20.5	°C/W
$T_{J}$	Maximum junction temperature	_	125	°C

<sup>(1)</sup> The package thermal impedance is calculated in accordance with JESD 51 and JEDEC2S2P (high-k board).

# RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
V <sub>DD_ANA</sub>	Device supply voltage	1.65	1.8	1.95	V
$V_{DD\_DIG}$	Device supply voltage	1.65	1.8	1.95	V
$V_{IH}$	Input voltage ADD AO DEOV DESET	0.65 V <sub>DD_DIG</sub>			V
$V_{IL}$	Input voltage ADR_A0, REQx, RESET			$0.35~V_{DD\_DIG}$	V
V <sub>IS</sub>	Sine-wave input voltage – MCLK_IN; ac-coupled amplitude	0.5		1.2	$V_{PP}$
C <sub>L</sub>	Sine-wave output load <sup>(1)</sup>		10	30	pF
C <sub>OUT</sub>	LDO output capacitance (stabilize the internal control loop)	0.8	2.2		μF
T <sub>A</sub>	Operating free-air temperature	-30		85	°C

<sup>(1) 10</sup> pF is the typical load-driving capability. The drive capability can be optimized for 30 pF by the I<sup>2</sup>C register (Byte 3, Bits 7–4).



#### **ELECTRICAL CHARACTERISTICS**

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
		OVERALL PARAMETER				
		$V_{BAT} = 5.5 \text{ V};$ Off (no REC	Q)	0.1	0.2	
I <sub>DD_ANA</sub>	Analog supply current <sup>(1)</sup> (seeFigure 8 through Figure 12)	$ \begin{array}{c} V_{DD\_ANA} = 1.95 \; V; \\ LDO \; is \; on; \; V_{IS} = 1 \; V_{PP}; \\ f_{MCLK\_IN} = 38.4 \; MHz; \\ R_L = 10 \; k\Omega; \; C_L = 10 \; pF^{(2)} \\ \end{array} \; \mbox{Per output} $		2	2.6	mA
I <sub>DD_DIG</sub>	Digital supply current (see Figure 8 through Figure 12)	$V_{BAT} = 5.5 \text{ V}; V_{DD\_DIG} = 1.95 \text{ V}; V_{DD\_AN/2} = off; \\ LDO = off; V_{IS} = 1 \text{ Vpp}; f_{MCLK\_IN} = 38.4 \\ MHz; \\ C_{L} = 10 \text{ pF}; R_{L} = 10 \text{ k}\Omega$	4		0.1	mA
I <sub>SB</sub>	Standby current	$V_{BAT}$ = 5.5 V; $V_{DD\_DIG}/V_{DD\_ANA}$ = 1.95 V All outputs disabled (no input clock; LDC off; no REQ; RESET is inactive; I <sup>2</sup> C is ir idle mode); includes 1-MΩ pullup at I <sup>2</sup> C and RESET	)	0.5	10	μА
f <sub>MCLK_IN</sub>	Input frequency	Sine wave	0.01	38.4	52	MHz
V <sub>OH</sub>	MCLK_REQ high-level output					V
	voltage	Push-pull output; $V_{DD\_DIG} = 1.65 \text{ V}$ , $I_{OH} = -2 \text{ mA}$	V <sub>DD_DIG</sub> – 0.45			
V	MCLK_REQ low-level output	Wired-AND output; $I_{OL} = 2 \text{ mA}$ $V_{DD\_DIG} = 1.65 \text{ V}$			0.45	V
V <sub>OL</sub>	voltage	Push-pull output; $V_{DD\_DIG} = 1.65 \text{ V}$ , $I_{OL} = 2 \text{ mA}$			0.45	V
$V_{IK}$	LVCMOS input voltage	$V_{DD\_DIG} = 1.65 \text{ V}; I_I = -18 \text{ mA}$			-1.2	V
	Input current ADR_A0, REQx (500-kΩ pulldown)	V - V - 105 V			6	
I <sub>IH</sub>	Input current $\overline{\text{RESET}}$ (1-M $\Omega$ pullup)	$V_{I} = V_{DD\_DIG}$ ; $V_{DD\_DIG} = 1.95 \text{ V}$			2	μΑ
L.	Input current ADR_A0, REQx (500- $k\Omega$ pulldown)	V <sub>I</sub> = 0 V; V <sub>DD DIG</sub> = 1.95 V			-2	μA
I <sub>IL</sub>	Input current $\overline{\text{RESET}}$ (1-M $\Omega$ pullup)	VI = 0 V, VDD_DIG = 1.95 V			-3	μΑ
C <sub>I</sub>	Input capacitance ADR_A0, REQx, RESET	V <sub>I</sub> = 0 V or V <sub>DD_DIG</sub>		3		pF
		SDAH/SCLH PARAMETER (Hs-M	ode)			
$V_{IK}$	SCLH/SDAH input clamp voltage	$V_{DD\_DIG} = 1.65 \text{ V}; I_I = -18 \text{ mA}$			-1.2	V
I <sub>I</sub>	SCLH/SDAH input current	$0.1 \text{ V}_{\text{DD\_DIG}} < \text{V}_{\text{I}} < 0.9 \text{ V}_{\text{DD\_DIG}}$			10	μA
$V_{IH}$	SDA/SCL input high voltage		0.7 V <sub>DD_DIG</sub>			V
$V_{IL}$	SDAH/SCLH input low voltage				$0.3\ V_{DD\_DIG}$	V
$V_{\text{hys}}$	Hysteresis of Schmitt-trigger inputs		0.1 V <sub>DD_DIG</sub>			V
$V_{OL}$	SDAH low-level output voltage	I <sub>OL</sub> = 3 mA, V <sub>DD_DIG</sub> = 1.65 V			$0.2~V_{DD\_DIG}$	V
	SCLH input capacitance	$V_I = 0 \text{ V or } V_I = V_{DD\_DIG}^{(3)}$		3	5	nE
C <sub>I</sub>	SDAH input capacitance	$V_{I} = 0 \text{ V or } V_{I} = V_{DD\_DIG}^{(3)}$		8	10	pF

<sup>(1)</sup> The total current consumption when no output is active is calculated by  $I_{DD\_ANA}(off) + I_{DD\_DIG}$ .

 <sup>(2)</sup> For C<sub>L</sub> = 30 pF, the typical current for one output is 2.2 mA (see Figure 8).
 (3) The I<sup>2</sup>C standard specifies a maximum C<sub>I</sub> of 10 pF.



over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT	
	SINE-WAV	E PARAMETER (MCLK_IN	is sine-wave s	ignal, C <sub>L</sub> = 10 pF	)			
f <sub>OUT</sub>	Output frequency					52	MHz	
Vos	Output gain level (see Figure 17)	MCLK_IN-to-CLKx; 10 kΩ, 10 pF; ac-coupled;	0.5 ≤ V <sub>IS</sub> ≤ 1.2 V <sub>PP</sub>	-1	-0.3	0	dB	
	Output voltage	f <sub>MCLK_IN</sub> > 1 MHz	$V_{IS} = 0.5 V_{PP}$	445	490	500	$mV_{PP}$	
	Additive rms jitter <sup>(4)</sup>	10 Hz to 10 MHz; f <sub>OUT</sub> = 38	3.4 MHz		0.3	0.6	20	
<sup>t</sup> jitadd(rms)	Additive firs jitter (*)	10 kHz to 10 MHz; f <sub>OUT</sub> = 3	88.4 MHz		0.1	0.2	ps <sub>RMS</sub>	
		At offset = 1 kHz			-142	-135		
pn <sub>add</sub>	Additive phase noise at f <sub>OUT</sub> = 38.4 MHz <sup>(5)</sup>	At offset = 10 kHz			-152	-145	dBc/Hz	
	30.4 WH 12	At offset = 100 kHz			-157	-150		
R <sub>IN</sub>	Input resistance	At dc level	12	15		kΩ		
C <sub>IN</sub>	Input capacitance	f <sub>MCLK_IN</sub> = 38.4 MHz		5	7	pF		
	ELECTF	RICAL CHARACTERISTIC of	of LDO (C <sub>OUT</sub> = 0	0.8 to 2.7 µF) <sup>(6)</sup>				
V <sub>BAT</sub>	Input voltage range		2.3		5.5	V		
$V_{LDO}$	LDO output voltage <sup>(7)</sup>	2.3 V < V <sub>BAT</sub> < 5.5 V, I <sub>LOAD</sub>	1.72	1.8	1.9	V		
	Maximum line regulation	2.3 V < V <sub>BAT</sub> ≤ 5.5 V, I <sub>LOAD</sub> = 5 mA			0.5%			
$\Delta V_{LDO}$	Maximum load regulation	0 < I <sub>LOAD</sub> < 5 mA, V <sub>BAT</sub> = 2 T <sub>J</sub> = 25°C	.3 V or 5.5 V;		0.5%			
I <sub>LOAD</sub>	Load current	$C_{OUT} = 0.8  \mu F$ to 2.7 $\mu F$		0	5		mA	
I <sub>LCL</sub>	LDO output current limit	$V_{LDO} = 0.9 \times V_{LDO(TYP)}$		10		60	mA	
I <sub>LGND</sub>	LDO ground pin current <sup>(8)</sup>	$V_{BAT} = 3.6 \text{ V}; 0 < I_{LOAD} < 5$	mA		50	150	μΑ	
I <sub>LSHDN</sub>	LDO shutdown current	2.3 V < V <sub>BAT</sub> < 5.5 V				0.2	μΑ	
			100 Hz	60	68			
		$V_{BAT} = 2.3 \text{ V (for min)}$	1 kHz	55	62			
DODD	Power-supply rejection ratio	$V_{BAT} = 2.5 \text{ V (for typ)}$	10 kHz	45	52		dB	
PSRR	(ripple rejection) (see Figure 20)	$V_{LDO} = 1.8 \text{ V}$ $I_{LOAD} = 5 \text{ mA}$	100 kHz	33	40			
		$V_{ripple} = 0.1 \text{ Vpp}$	1 MHz	37	46			
			10 MHz	60	67			
V <sub>N</sub>	Output noise voltage (see Figure 21)	BW = 10 Hz to 100 kHz; $V_L$ $I_{LOAD}$ = 5 mA	<sub>DO</sub> = 1.8 V;			30	μV <sub>RMS</sub>	

(4) Additive rms jitter is the integrated rms jitter that the device adds to the signal chain. It is calculated by t<sub>jitadd(rms)</sub> = √(t<sub>jitout(rms)</sub><sup>2</sup> - t<sub>jitin(rms)</sub><sup>2</sup>). Specified with the supply ripple noise of 30 µV(rms) from 10 Hz to 100 kHz.

(5) Additive phase noise is the amount of phase noise that the device adds to the signal chain. It is calculated by L<sub>add</sub> (dB) = 10 log (10<sup>0.1 Lout</sup> – 10<sup>0.1 Lin</sup>).

(6) Minimum C<sub>OUT</sub> should be 100 nF to allow for stable LDO operation.

- (7) LDO output voltage includes maximum line and load regulation.
   (8) LDO ground pin current does not change over V<sub>BAT</sub>.



#### TIMING REQUIREMENTS

over operating free-air temperature range (unless otherwise noted)  $V_{LDO} = 1.8 \text{ V}$ ;  $C_{L} = 10 \text{ pF}$ ;  $R_{L} = 10 \text{ k}\Omega$ 

PARAMETER		TEST CONDITIONS	MIN TYP(1	) MAX	UNIT			
TIMING PARAMETER								
t <sub>PD</sub>	Propagation delay time	MCLK_IN-to-CLKx; f <sub>MCLK_IN</sub> = 38.4 MHz		3	ns			
t <sub>LH</sub>	Propagation delay time, low-to-high	REQx-to-MCLK_REQ (wired-OR, $C_L$ = 15 pF, $R_L$ = 10 k $\Omega$ );		15	ns			
	CLKx on-time – REQ-to-CLKx	f <sub>MCLK IN</sub> = 38.4 MHz; V <sub>VDD ANA</sub> is on;	0.3	3 0.4	μs			
	CLKx on-time – RESET-to-CLKx <sup>(3)</sup>	$V_{IS} = 1 \text{ V}$ ; $V_{OS} = -1 \text{ dB}$ (see Figure 5 and	0.0	6.0	μs			
t <sub>CLK</sub> <sup>(2)</sup>	CLKx off-time – REQ-to-CLKx Figure 6)		25	ns				
CLKx on-time – V <sub>DD_ANA</sub> to-CLKx	CLKx on-time – V <sub>DD_ANA</sub> to-CLKx	$\begin{split} f_{MCLK\_IN} &= 38.4 \text{ MHz} \; ; \; V_{IS} = 1 \; V; \\ V_{OS} &= -1 \; dB; \; \text{measurement starts when} \\ V_{DD\_ANA} \; \text{is } 90\% \; \text{of } 1.7 \; V \; \text{(see Figure 7)} \end{split}$	20	50	μs			
t <sub>SP</sub>	Pulse duration of spikes that must be suppressed by the input filter for RESET (3)			100	ns			
t <sub>sk(o)</sub>	Output skew <sup>(4)</sup>	f <sub>MCLK_IN</sub> = 38.4 MHz; CLK1-to-CLK4	2:	5 50	ps			
t <sub>LDO</sub>	LDO on-time <sup>(5)</sup> – REQ-to-LDO; – RESET-to-LDO	$V_{LDO} = 1.7 \text{ V}, I_{LDO} = 5 \text{ mA}, \\ 2.3 \text{ V} < V_{BAT} < 5.5 \text{ V}; C_{OUT} = 2.7 \mu\text{F}$	10	300	μs			

- All typical values are at nominal  $V_{DD\_ANA}$  and  $V_{DD\_DIG}$ . CLK on-time is measured with valid input signal ( $V_{IS}$  = 1 Vpp). In case a TXCO is used, the LDO and TCXO are already on. Pulses above 500 ns are interpreted as a valid reset signal. Total time from RESET-to-CLKx is the sum of  $t_{SP}$  +  $t_{CLK\_/RESET}$ .
- Output skew is calculated as the greater of the difference between the fastest and the slowest tplh or the difference between the fastest and the slowest  $t_{\text{PHL}}$ . LDO off-time depends on the discharge time of the R-C components (seeFigure 4).

	PARAMETER	MIN	MAX	UNIT		
SDAH/SCLH TIMING REQUIREMENTS, Hs-Mode (C <sub>BUS</sub> = 100 pF for each I <sup>2</sup> C line; see Figure 24 and Figure 25)						
f <sub>SCLH</sub>	SCLH clock frequency	0	3.4	MHz		
t <sub>su(START)</sub>	START setup time (SCLH high before SDAH low)	160		ns		
t <sub>h(START)</sub>	START hold time (SCLH low after SDAH low)	160		ns		
LOW	Low period of the SCLH clock	160		ns		
HIGH	High period of the SCLH clock	60		ns		
h(SDAH)	SDAH hold time (SDAH valid after SCLH low)	0 <sup>(1)</sup>	70	ns		
su(SDAH)	SDAH setup time	10		ns		
	SCLH rise time	10	40	ns		
r	SDAH rise time	10	80			
	SCLH fall time	10	40	ns		
f	SDAH fall time	10	80			
su(STOP)	STOP setup time	160		ns		
t <sub>SP</sub>	Pulse duration of spikes that must be suppressed by the input filter for SDAH and SCLH	0	10	ns		

<sup>(1)</sup> A device must internally provide a data hold time to bridge the undefined period between V<sub>IH</sub> and V<sub>IL</sub> of the falling edge of the SCLH signal. An input circuit with a threshold as low as possible for the falling edge of the SCLH signal minimizes this hold time.



# PARAMETER MEASUREMENT INFORMATION

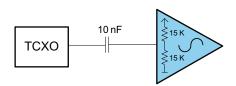


Figure 1. Input Circuit

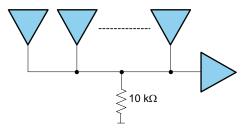


Figure 3. Wired OR

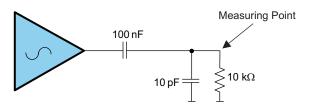
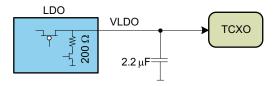


Figure 2. Output Circuit



i.e. time constant(RxC) is 440  $\mu s$  for 63% discharge.

Figure 4. LDO Output Circuit



# **TYPICAL CHARACTERISTICS**

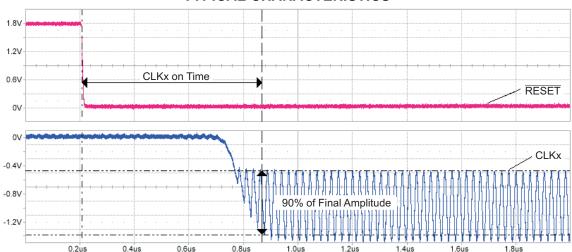


Figure 5. CLKx On-Time From  $\overline{\text{RESET}}$  Off-to-On

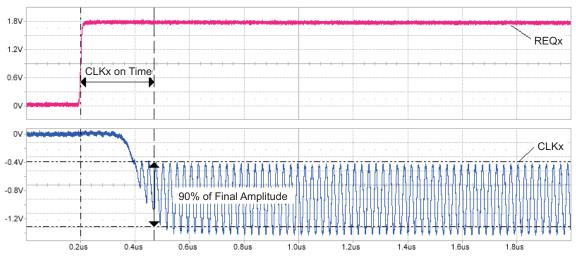


Figure 6. CLKx On-Time From REQ Off-to-On

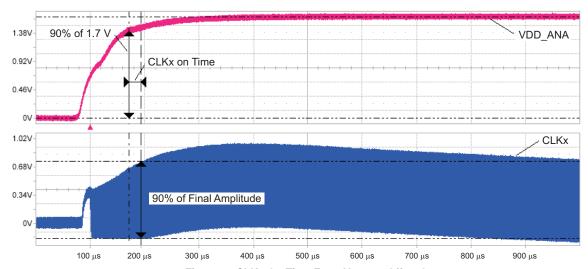


Figure 7. CLKx On-Time From  $V_{DD\_ANA}$  Off-to-On



SUPPLY CURRENT (IDD\_ANA, IDD\_DIG)

#### vs OUTPUT LOAD (CL) AT 38.4 MHz INPUT CLOCK

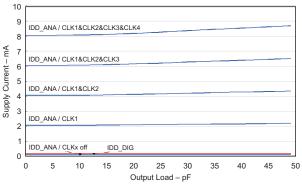
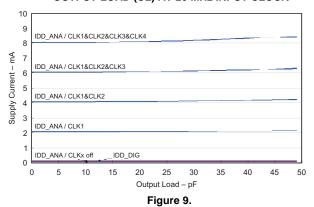


Figure 8.

# SUPPLY CURRENT (IDD\_ANA, IDD\_DIG) vs OUTPUT LOAD (CL) AT 26 MHz INPUT CLOCK



# SUPPLY CURRENT (IDD\_ANA, IDD\_DIG) vs INPUT FREQUENCY (MCLK\_IN)

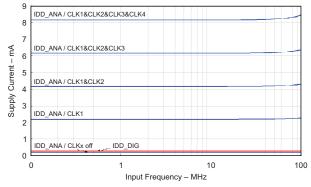


Figure 10.



SUPPLY CURRENT (IDD\_ANA, IDD\_DIG)

#### vs

# INPUT VOLTAGE LEVEL AT 38.4 MHz INPUT CLOCK

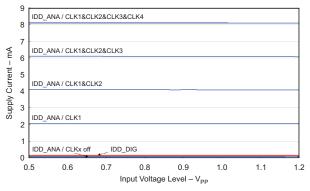


Figure 11.

# SUPPLY CURRENT (IDD\_ANA, IDD\_DIG) vs

# INPUT VOLTAGE LEVEL AT 26 MHz INPUT CLOCK

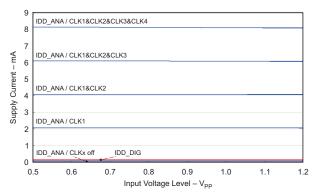


Figure 12.



TCXO INPUT CLOCK

#### vs OUTPUT CLOCK AT 38.4 MHz

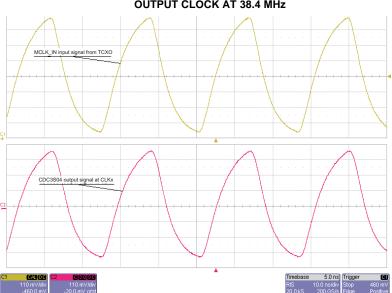


Figure 13.

# TCXO INPUT CLOCK

# **OUTPUT CLOCK AT 26 MHz**

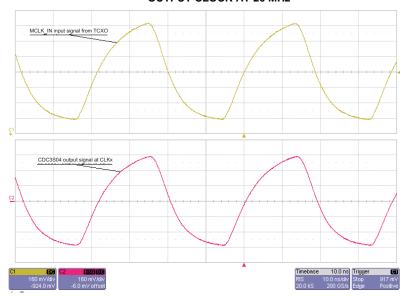


Figure 14.



# SINE WAVE INPUT CLOCK

#### vs OUTPUT CLOCK AT 38.4 MHz

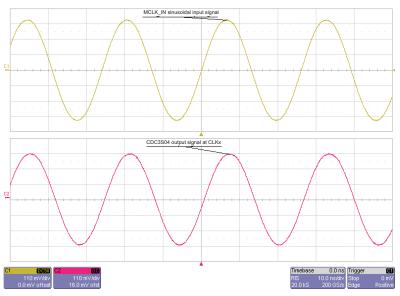


Figure 15.

# SINE WAVE INPUT CLOCK

# **OUTPUT CLOCK AT 26 MHz**

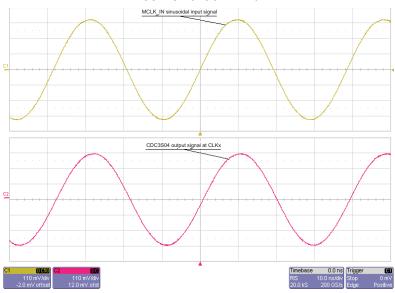


Figure 16.



# **OUTPUT GAIN**

# vs INPUT FREQUENCY (MCLK\_IN)

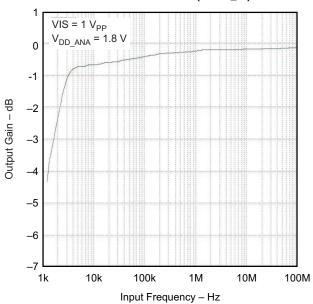


Figure 17.

# INPUT

# **OUTPUT PHASE-NOISE PERFORMANCE WITH 38.4-MHz TCXO**

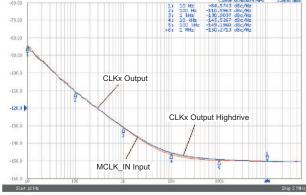


Figure 18.



# **INPUT**

# **OUTPUT PHASE-NOISE PERFORMANCE WITH 26-MHz TCXO**

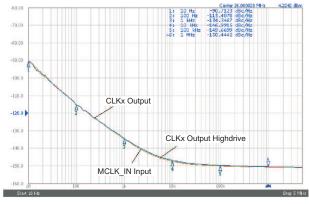


Figure 19.

# LDO POWER SUPPLY REJECTION

# FREQUENCY (PSRR)

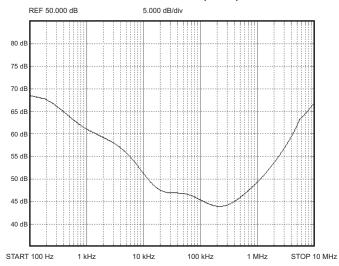


Figure 20.



LDO OUTPUT SPECTRAL NOISE DENSITY

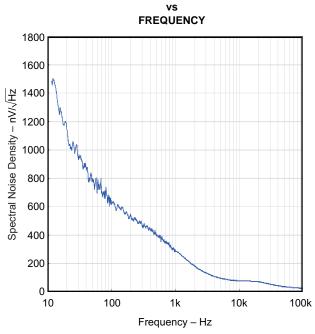


Figure 21.



#### **DETAILED DESCRIPTION**

# SDAH/SCLH SERIAL INTERFACE (Hs-Mode)

This section describes the SDAH/SCLH interface of the CDC3S04 device. The CDC3S04 operates as a slave device of the two-wire serial SDAH/SCLH bus, compatible with the popular I<sup>2</sup>C specification (UM10204-I<sup>2</sup>C-bus specification and user manual Rev. 03–19 June 2007). It operates in the high-speed mode (up to 3.4 Mbit/s) and supports 7-bit addressing. The CDC3S04 is fully downward compatible with fast- and standard-mode (F/S) devices for bidirectional communication in a mixed-speed bus system.

#### **Data Protocol**

The device supports byte-write and byte-read operations only. There is no block-write or block-read operation supported; therefore, no command code byte is needed.

When a byte has been sent, it is written into the internal register and is immediately effective.

#### Slave Receiver Address (7 bits)

Device	A6	A5	A4	A3	A2	A1	A0 <sup>(1)</sup>	R/W
CDC3S04	1	1	0	1	1	0	0	1/0

<sup>(1)</sup> Address bit A0 is selectable by the ADR\_A0 input (pin D1). This allows addressing of two devices connected to the same I<sup>2</sup>C bus. The default value is 0, set by an internal pulldown resistor.

# **Byte-Write Programming Sequence**

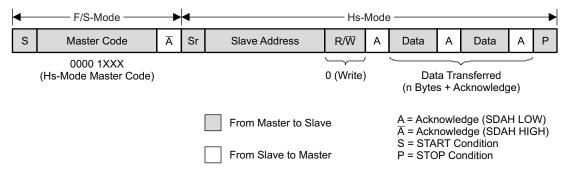


Figure 22. Byte-Write Protocol

# **Byte-Read Programming Sequence**

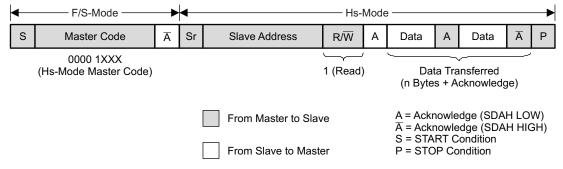
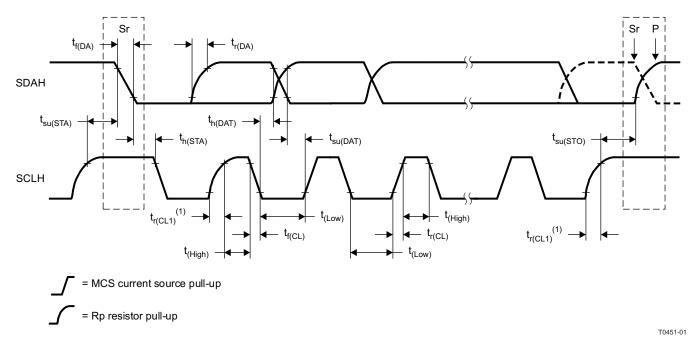


Figure 23. Byte-Read Protocol





(1) First rising edge of the SCLH signal after Sr and after each acknowledge bit.

Figure 24. Definition of Timing for a Complete Hs-Mode Transfer

The following diagram shows how the CDC3S04 clock buffer is connected to the SDAH/SCLH serial interface bus. Multiple devices can be connected to the bus, but the speed may need to be reduced (3.4 MHz is the maximum) if many devices are connected.

Note that the pullup resistors ( $R_P$ ) depend on the supply voltage, bus capacitance, and number of connected devices. For more details, see the  $I^2C$  bus specification.

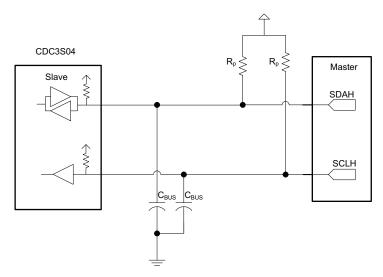


Figure 25. SDAH/SCLH Hardware Interface

# **SDAH/SCLH Configuration Registers**

The output stages are user configurable. Table 3 explains the programmable functions of the CDC3S04.



# Table 3. Configuration Register (Shaded Cells Marks Power-Up/Default Setting)

Offset	BIT <sup>(1)</sup>	Acronym	Default (2)	RESET (3)	Description	0	1	Туре				
	7	REQ4INT	1b	1b	CLK4 off/on <sup>(4)</sup>	Off	On					
	6	REQ3INT	0b	-	CLK3 off/on <sup>(4)</sup>	Off	On	R/W				
	5	REQ2INT	0b	_	CLK2 off/on <sup>(4)</sup>	Off	On					
001-	4	REQ1INT	1b	1b	CLK1 off/on <sup>(4)</sup>	Off	On					
00h	3	REQ4POL	1b	_	Selects polarity of REQ4	Active-low	Active-high					
	2	REQ3POL	1b	-	Selects polarity of REQ3	Active-low	Active-high					
	1	REQ2POL	1b	-	Selects polarity of REQ2	Active-low	Active-high	1				
	0	REQ1POL	1b	-	Selects polarity of REQ1	Active-low	Active-high					
	7	MREQ4	1b	-	Defines if REQ4 is used to decode MCLK_REQ		Used for					
	6	MREQ3	1b		Defines if REQ3 is used to decode MCLK_REQ	Not used for						
	5	MREQ2	1b	Defines if REQ2 is used to decode  MCLK_REQ								
01h	4	MREQ1	1b	-	Defines if REQ1 is used to decode MCLK_REQ							
	3	MCLKOUT1			Selects MCLK_REQ output type 00 = wired-OR (default setting) 01 = wired-AND 1x = push-pull							
	2	MCLKOUT0	00b	_								
	0–1	_	00b	_	Reserved							
	7	MREQCTRL1			MCLK_REQ generation (see Figure 27) 0x = decoder controlled (default setting) 10 = low 11 = high							
	6	MREQCTRL0	00b	_								
	5	LDOEN1			Switches LDO on or off:							
02h	4	LDOEN0	00b	_	00 = LDO is on (default setting) 01 = LDO is off 1x = decoder controlled (see Figure 27)			R/W				
	3	REQ4PRIO	1b	1b	Defines external vs internal REQ4 priority	REQ4	REQ4INT					
	2	REQ3PRIO	0b	-	Defines external vs internal REQ3 priority	REQ3	REQ3INT					
	1	REQ2PRIO	0b	-	Defines external vs internal REQ2 priority	REQ2	REQ2INT	1				
	0	REQ1PRIO	1b	1b	Defines external vs internal REQ1 priority	REQ1	REQ1INT					
	7	HIGHDRIVE4	0b	-	Enables high-drive capability CLK4	Typical	High					
	6	HIGHDRIVE3	0b	-	Enables high-drive capability CLK3	Typical	High					
03h	5	HIGHDRIVE2	0b	-	Enables high-drive capability CLK2	Typical	High	R/W				
	4	HIGHDRIVE1	0b	-	Enables high-drive capability CLK1	Typical	High					
	0–3	-	0b	-	Reserved							
)4h–Bh <sup>(5)</sup>		_		-	Reserved			R/W				

All data is transferred with the MSB first.

<sup>(2)</sup> 

A device reset to default condition is initiated by a V<sub>DD\_DIG</sub> power-up sequence.

"-" means that dedicated bits do not change at RESET.

Inactive as long as the REQxPRIO bit is low, external REQx pins are valid (see Figure 26)

Writing data beyond 03h may affect device function.



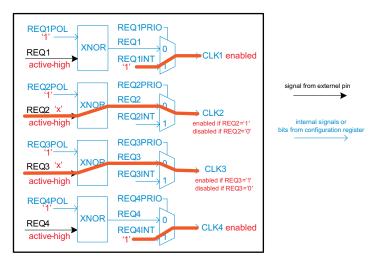


Figure 26. Clock Output Enable Signal (Shaded Line Marks Power-Up/Default Setting)

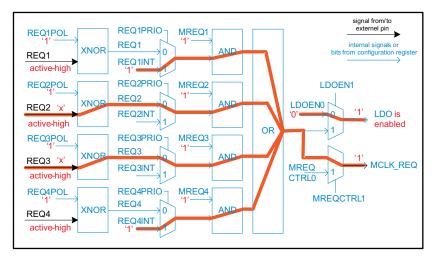


Figure 27. Decoding Scheme for MCLK\_REQ and LDOEN (Shaded Line Marks Power-Up/Default Setting)



# **APPLICATION INFORMATION**

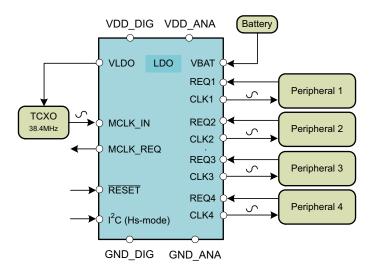


Figure 28. Clock Distribution Scheme



# **REVISION HISTORY**

Changes from Original (October 2009) to Revision A	Page
Changed the format on page 1 (moved 2 paragraphs from page 2 to page)	e 1) 1
Changed the X axis from 0.1us to 100us900us	9
Changed Offset 00h Bit 4 Default value from 0h to 1b	
Changes from Revision A (July 2010) to Revision B	Page
Changed Table 3 "Offset" values listed in "Default" and "RESET" column	s from "h" to "b"



# PACKAGE OPTION ADDENDUM

12-Apr-2011

#### **PACKAGING INFORMATION**

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins	Package Qty	Eco Plan <sup>(2)</sup>	Lead/ Ball Finish	MSL Peak Temp <sup>(3)</sup>	Samples (Requires Login)
CDC3S04YFFR	ACTIVE	DSBGA	YFF	20	3000	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM	

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL. Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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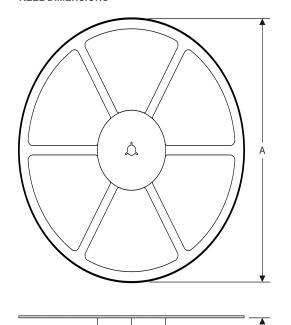
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# PACKAGE MATERIALS INFORMATION

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# TAPE AND REEL INFORMATION

# **REEL DIMENSIONS**



# **TAPE DIMENSIONS**



A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

# TAPE AND REEL INFORMATION

\*All dimensions are nominal

Device	Package Type	Package Drawing			Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDC3S04YFFR	DSBGA	YFF	20	3000	180.0	8.4	1.63	2.08	0.69	4.0	8.0	Q1

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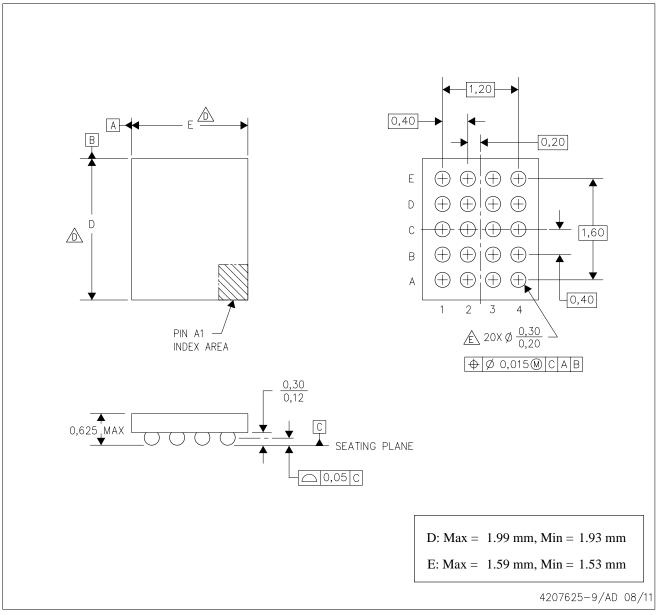


#### \*All dimensions are nominal

Device	F	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDC3S04YFFR		DSBGA	YFF	20	3000	210.0	185.0	35.0

# YFF (R-XBGA-N20)

# DIE-SIZE BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. NanoFree™ package configuration.

The package size (Dimension D and E) of a particular device is specified in the device Product Data Sheet version of this drawing, in case it cannot be found in the product data sheet please contact a local TI representative.

- E. Reference Product Data Sheet for array population. 5 x 4 matrix pattern is shown for illustration only.
- F. This package contains Pb-free balls.

NanoFree is a trademark of Texas Instruments



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